NO. 19B030033 CLASS CHEMISTRY, BATCH P17/8 INDIAN INSTITUTE NAME VATSAL TECHNOLOGY BOMBAY EXPT. No. 3 **LABORATORY** DATE August 30, 2019 PHYSICS DEPT. PHOTOELECTRIC EFFECT Aim : To show the particle behaviour of the light and find the Planck's constant h using photoelectric Apparatus: Halogen Tungeten lamp (12 V/35W), phototube inside a box (vacuum conditions), voltage power supply, current meter (nanometer), optical bench as marked with a scale marking, and a set of color filters. Theory & Electrons are emitted from a metal surface when light (riebble or ultraviolet) of right frequency is shone, on a metal. This is known as photoelectric effect. The classical wave theory

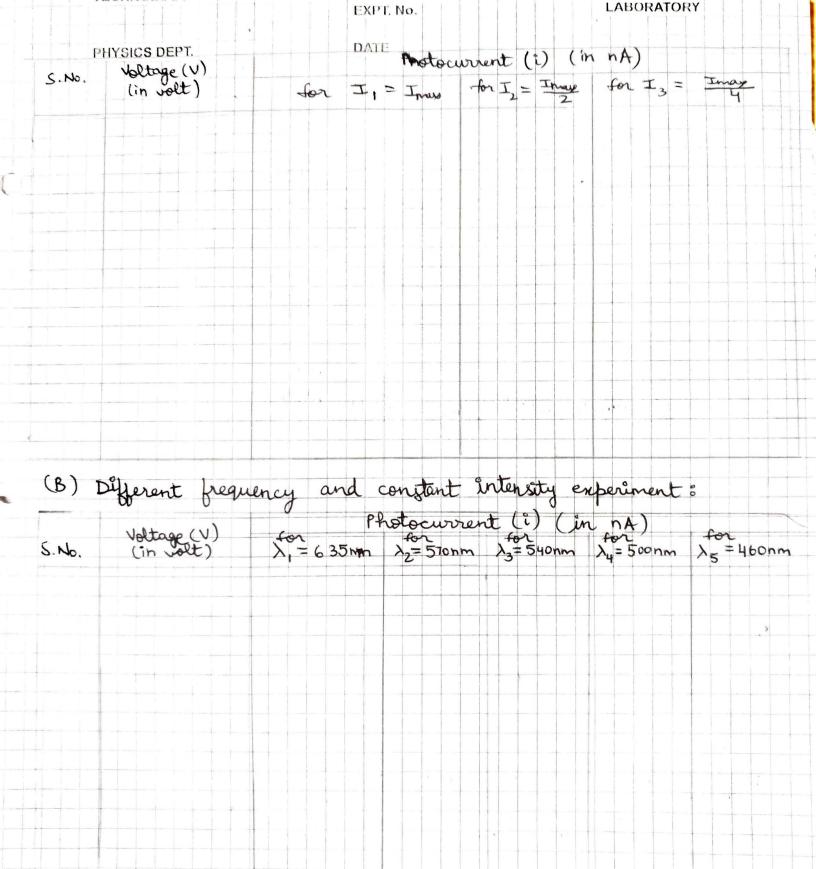
predicts that energy of the electrons should

increase as the intensity of light increases. In

contrast to this popular belief, it was found that energy of the emitted electron was dependent upon the frequency of the incident light and electrons will not be emitted if frequency was not above a certain threshold. It was observed that higher energy electrons will be enritted when higher frequency light was incident on a metal and low energy electron will be seen when a lower frequency light is incident on the metal. Plan h = W + KEmas . where his is the energy of photons, Wis the work function of a given metal plate and KFmay is the maximum kinetic energy attained by the photoelectrons. In a given experiment, a collector plate is charged negatively by applying a negative potential (so called stopping potential) so that electrons do not reach to the collector plate and then photocurrent is noted to be zero. KEmay will be equivalent to eV where V is the stopping potential and e is the charge of the electron (1.6× 10 - 19 C) $\Rightarrow V = \frac{h}{e}v - \frac{W}{e}$

Calculation and error analysis: 1. Use the least square fitting of a straight line method to find the slope "m" and its uncertainty in slope 'sm". $M = \frac{N \leq x_i y_i - \leq x_i \leq y_i}{N \leq x_i^2 - (\leq x_i)^2}; \quad \overline{x} = \leq x_i / N; \quad D = \leq (x_i - \overline{x})^2$ $c = \overline{y} - m\overline{n}$; $\overline{y} = E y_1/N$ $\left(\Delta m\right)^{2} \approx \left[\frac{1}{D} \frac{\sum d_{i}^{2}}{\left(N-2\right)}\right] \cdot \left(\Delta c\right)^{2} \approx \left[\frac{1}{N} + \frac{\pi^{2}}{D}\right] \frac{\sum d_{i}^{2}}{\left(N-2\right)}$ where di = yi-mili-c Find the y intercept "c" and the corresponding error "sc" 3. Using this method, determine Planck's constant h and the work function W of the metal used. Tabulate error calculations of these two parameters.

Precautions: 1) The instrument needs careful gentle handling while during the working operation 2) Drawtube shall not be kept open. After finishing the enferiment cap it with the given black cap. 3) Filters screens should not be touched while changing the filter. If found dirty a cotton suab with alcohol is a good way to clean. After finishing the enperiment switch of the bower supply and cover the drawtube with the black lens cover provided. Phototube is a sensitive part. The sensitivity decreases with an emposure to light. Observations: (A) Constant frequency and different intensity experiment: Photocurrent (i) (in nA) $I_1 = I_{man} \qquad \text{for } I_2 = \frac{I_{max}}{2} \quad \text{for } I_3 = \frac{I_{max}}{4}$ Voltage (V)
(in volt) S. No. for I = Iman



			PJ	rotocur	vent (i	.) (in n	A)	
S.No.	Voltage(v) (in welt)	for λ=635 nm						for 1/5 = 460 nm
				4				
<u>c</u>)				CLALLIS	u betontio	0 2		
S.No.	wovelength (x (in nm)	requence (* XIC	H3)	(V _S) (y fotentia in volt) Ji)	L Z	n _i y _i	
		Che	t)	,	ar)			
1.								
2.								
3.								
5.								
		2 xi=		Eyi:		Eni=	Engl=	

Calculations:

$$M = \frac{N \leq x_{i}y_{i} - \sum x_{i} \geq y_{i}}{N \leq x_{i}^{2} - (\sum x_{i})^{2}}$$

$$= \frac{1}{2} \frac{y_{i}}{N} = \frac{1}{2} \frac{y_{i}}{N$$

Planck's con	stant, h = m	xe=				
Work Jun	ction, $W = -6$	C×e =				
Uncerta	inty in calcu					
	At = Ar					
	AW = AC	xe =				
Result ar	d discuss	sion:				
Pa	rameter	Value	Unc	Uncertainty		
Plane	k's constant (h)		. *	SQ =		
Wer	k function(w)			AW= .		
			5.			
			*			